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Prenos in multipleksiranje (TM) ï Generiļ ne zahteve za prenosno funkcionalnost opreme ï 5-2. del: Funkcije plasti poti pri pleziohroni digitalni hierarhiji (PDH) ï Proforma specifikacija izjave o skladnosti izvedbe (ICS)

Transmission and Multiplexing (TM); Generic requirements of transport functionality of equipment; Part 5-2: Plesiochronous Digital Hierarchy (PDH) path layer functions; Implementation Conformance Statement (ICS) proforma specification

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ETSI

Postal address

F-06921 Sophia Antipolis Cedex - FRANCE

Office address

650 Route des Lucioles - Sophia Antipolis
Valbonne - FRANCE
Tel.: +33 4 92 94 42 00 Fax: +33 4 93 65 47 16
Siret N° 348 623 562 00017 - NAF 742 C
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Internet

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Foreword

This European Standard (Telecommunications series) has been produced by ETSI Technical Committee Transmission and Multiplexing (TM).

The present document is one of a family of documents that has been produced in order to provide inter-vendor and inter-operator compatibility of Synchronous Digital Hierarchy (SDH) equipment.

The present document is part 5-2 of a multi-part EN covering the generic requirements of transport functionality of equipment, as identified below:

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Part 1-1: "Generic processes and performance";

Part 1-2: "General information about Implementation Conformance Statement (ICS) proforma";

Part 2-1: "Synchronous Digital Hierarchy (SDH) and Plesiochronous Digital Hierarchy (PDH) physical section layer functions";

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Part 2-2: "Synchronous Digital Hierarchy (SDH) and Plesiochronous Digital Hierarchy (PDH) physical section layer functions; Implementation Conformance Statement (ICS) proforma specification";

Part 3-1: "Synchronous Transport Module-N (STM-N) regenerator and multiplex section layer functions";

Part 3-2: "Synchronous Transport Module-N (STM-N) regenerator and multiplex section layer functions; Implementation Conformance Statement (ICS) proforma specification";

Part 4-1: "Synchronous Digital Hierarchy (SDH) path layer functions";

Part 4-2: "Synchronous Digital Hierarchy (SDH) path layer functions; Implementation Conformance Statement (ICS) proforma specification";

Part 5-1: "Plesiochronous Digital Hierarchy (PDH) path layer functions";

Part 5-2: "Plesiochronous Digital Hierarchy (PDH) path layer functions; Implementation Conformance Statement (ICS) proforma specification";

Part 6-1: "Synchronization layer functions";

Part 6-2: "Synchronization layer functions; Implementation Conformance Statement (ICS) proforma specification";

Part 7-1: "Equipment management and auxiliary layer functions";

Part 7-2: "Auxiliary layer functions; Implementation Conformance Statement (ICS) proforma specification".

Parts 2 to 7 specify the layers and their atomic functions.

NOTE 1: The present document does not currently address configuration management.

NOTE 2: The SDH radio equipment functional blocks are addressed by ETSI WG TM4.